



2064-7

Joint ICTP/IAEA Advanced School on in-situ X-ray Fluorescence and Gamma Ray Spectrometry

26 - 30 October 2009

Portable XRF instrumentaton (including excitation sources, detectors, electronics, software)

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ROBERTO CESAREO Universita di Sassari, ITALIA

ENERGY-DISPERSIVE X-RAY FLUORESCENCE : PHYSICAL BACKGROUND





PRINCIPALI RAGGI X

ELEMENTO	Ка	Кβ	La	Lβ	Lγ
SODIO	1.04				
MAGNESIO	1.25				
ALLUMINIO	1.49				
SILICIO	1.74				
FOSFORO	2.01				
ZOLFO	2.31				
CLORO	2.62	2.81			
ARGON	2.96	3.2			
POTASSIO	3.31	3.6			
CALCIO	3.69	4.0			
TITANIO	4.51	4.93			
CROMO	5.41	5.95			
MANGANESE	5.90	6.5			
FERRO	6.40	7.06			
COBALTO	6.93	7.65			
NICHEL	7.48	8.26			
RAME	8.05	8.9			
ZINCO	8.64	9.6			
ARSENICO	10.54	11.7			
SELENIO	11.22	12.5			
BROMO	11.92	13.3			
RUBIDIO	13.39	15.0	1.7		
STRONZIO	14.16	15.8	1.8		
ITTRIO	14.96	16.7	1.92		
ZIRCONIO	15.77	17.7	2.04		
NIOBIO	16.61	18.6	2.16		
MOLIBDENO	17.5	19.6	2.3	2.5	
ARGENTO	22.2	24.9	2.98	3.2	
CADMIO	23.2	26.1	3.13	3.45	
STAGNO	25.3	28.5	3.4	3.8	
ANTIMONIO	26.4	29.7	3.6	4.0	
BARIO	32.2	36.4	4.45	5.0	
TUNGSTENO	59.3	67.2	8.4	9.9	
ORO	68.8	78.0	9.7	11.5	
MERCURIO	70.8	80.3	9.95	11.9	
PIOMBO	75	84.9	10.5	12.6	
URANIO	98.4	111.3	13.5	17.5	







Fig. 2.4. – X-ray fluorescence spectra of some typical pure elements collected with a HpG semiconductor detector. From the top X_K -rays of Cu (8.04 and 8.94 keV), Rb (13.36 and 15.1 keV), Ag (22.1 and 25.2 keV) and Ba (32.0 and 36.8 keV), and X_L -rays of Pb (10.5 and 12.615 keV).

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THE INTERNAL RATIO OF THE X-LINES **IS GENERALLY FIXED:** FOR EXAMPLE THE RATIO Kalfa TO Kbeta OF COPPER IS 6.4 THE RATIO Lalfa TO Lbeta OF LEAD IS HOWEVER THIS RATIO MAY CHANGE IF THE LINES ARE DIFFERENTLY ABSORBED



When a sample containing an element a with a concentration c_a i Is irradiated by a beam of X-rays having an energy E_0 and intensity of N_0 photons/s, the number N_a of fluorescent X-rays emitted by the element a , is approximately given by:

 $\mathbf{N}_{\mathbf{a}} = \mathbf{N}_{\mathbf{0}} \mathbf{k} \boldsymbol{\omega}_{\mathbf{a}} \mathbf{J}_{a} \boldsymbol{\sigma}_{\mathbf{a}} \mathbf{c}_{\mathbf{a}} \mathbf{M}$

where:

- -k is an overall geometrical factor;
- $-\omega_a$ is the fluorescent yield of the element a in the shell of interest (i.e. percent probability of a fluorescence effect compared with an Auger effect));
- $-\sigma_a$ (cross section in cm²) is related to the probability for fluorescent effect of element a ;
- $-J_a$ is the branching ratio, i.e. the intensity of the X-line of interest -over the total X-ray intensity;
- -M is a matrix term (i.e. depending on the sample), related to the attenuation of incident and secondary fluorescent radiation and on the sample composition











FIGURE 3. Fluorescence yields as a function of atomic number. Only mean yields can be given for the L and M shells. Exact yields depend on how the initial electron vacancy distribution is formed and filled.









In the case of thin samples, primary and secondary X-rays are deglissing characterized by a penetration depth much larger than the sample thickness. In this case the matrix term of previous Eq. is approximately equal to 1, and following Eq. is valid:

$$\mathbf{N}_{\mathbf{a}} = \mathbf{N}_{\mathbf{0}} \mathbf{k} \boldsymbol{\omega}_{\mathbf{a}} \mathbf{J}_{a} \boldsymbol{\sigma}_{\mathbf{a}} \mathbf{c}_{\mathbf{a}}$$

i.e. counts of element a are linearly proportional to its concentration . Intensity N_{sc} of scattered photons in the case of thin samples (mainly due to Compton scattering) is approximately given by: $N_{sc} \approx N_0 \ k \ \mu_{sc}(E_0) \ m$

where m (in g/cm^2) is the mass per unit area of the sample.



Artifacts like statues, columns, alloys and etc., generally appears to AR EDXRF analysis as "infinitely thick samples", in the sense that the thickness of the objects is much greater than the "radiation penetration".

When a generic element a with concentration c_a , in an infinitely thick and homogeneous sample is irradiated with N_0 incident photons, the secondary fluorescent X-ray intensity N_a is given by

 $\mathbf{N}_{a} = \mathbf{N}_{o} \mathbf{k} \ \boldsymbol{\omega}_{a} \mathbf{J}_{a} \mathbf{c}_{a} \left[\mu_{ph,a} \left(\mathbf{E}_{0} \right) / \mu_{t} \left(\mathbf{E}_{0} \right) + \mu_{t} \left(\mathbf{E}_{a} \right) \right]$

 $\mu_{ph,a}(E_o)$ represents the photoelectric attenuation coefficient of element *a* at incident energy E_o ; $\mu_t(E_o)$ and $\mu_t(E_a)$ represent the total attenuation coefficient of the sample at incident and fluorescent energies (E_0 and E_a) respectively.

where:



AN EQUIPMENT FOR EDXRF-ANALYSIS IS, THEREFORE COMPOSED OF : -A SOURCE OF X-RAYS, OR GAMMA RAYS -A X-RAY DETECTOR -AN ELECTRONIC CIRCUIT -A PULSE HEIGHT ANALYZER (MULTI-CHANNEL ANALYZER



SOURCES OF EXCITATION : -RADIOACTIVE SOURCES -MINI-X RAY TUBES -SYNCHROTRON RADIATION THE IDEAL SOURCE SHOULD BE: -MONOENERGETIC WITH AN ENERGY CLOSE (BUT NOT TOO MUCH TO THE PHOTOELECTRIC DISCONTINUITY OF THE ELEMENT UNDER STUDY; -OF ADEQUATE INTENSITY



Table 8 – Radioactive sources for portable EDXRF equipments [44]

Source	Principal photon energies (keV)	Intensity (ph/s sr mCi)	Half-life	Elements that can be analyzed
Fe-55	5.9	2×10^6	2.7 y	Z < 23 (K-lines)
Cd-109	22,88	8 x 10 ⁶	453 d	Z < 42 (K-lines)
				Z =50-92 (L-lines)
Am-241	59.5	3×10^{6}	433 y	Z < 69 (K-lines)
				Z=70-92 (L-lines)
Co-57	122	8 x 10 ⁶	270 d	$Z \approx 50-92$ (K-lines)



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X-RAY TUBES -ARE EMITTING RADIATION ONLY WHEN NEEDED -ARE EMITTING BREMSSTRAHLUNG (NON MONO-ENERGETIC RADIATION) -ARE EMITTING RADIATION OF ADEQUATE INTENSITY -ARE OF SMALL SIZE -MAY BE DEDICATED -X-RAY TUBES ARE AVAILABLE OF ANY HIGH VOLTAGE, INTENSITY AND ANODE









Applications

X-RAY

Portable XRF RoHS/WEEE

- · Alloy sorting
- Soil analysis
- EnvironmentalLead in paint
- Plastics analysis
- Material ID
- Security

Handheld Imaging

- Medical/DentalMaterial ID
- Security
- Bench top EDXRF
- Instrument Calibration
- Micro-Fluorescence

Micro-Diffraction



50kV MAGNUM[®] X-ray Tubes

The MAGNUM[®] x-ray tube is now available in a 50kV package. The MAGNUM 50kV x-ray tube is a low power, miniature x-ray tube used for a variety of applications including handheld and benchtop instrumentation. MAGNUM x-ray tubes are small, lightweight, and can be packaged into custom enclosures.

atures Benef

Close coupling of source to detector Small, compact design Lightweight Portable, versatile Close coupling of collimator & target Efficient utilization of x-rays Low detection limit Stable output Long battery life Low power consumption Low spectral contamination No unwanted peaks Short sampling time High x-ray output Flexible form factor Customizable configurations

Standard Package Includes:

- · Transmission Target (End Window)
- · MAGNUM tube potted in a brass shield
- High voltage power supply
- · High voltage wire length is 11.5 inches

Customizable Options:

- · Target materials and thickness
- Tube shield design
- Power supply packaging
 High voltage wiring length
- Integrated tube and power supply
- integrated thee and points supp.





VAR AN X-RAY PRODUCTS

VF-50J Industrial X-Ray Tube



APPLICATION

The VF-50 series x-ray tube is a beryllium window x-ray tube designed for use as a radiation source for x-ray fluorescence systems.

CONSTRUCTION

The beryllium x-ray window is located at the end of the tube and the beam is projected along the longitudinal axis of the tube. The cathode operates at ground potential and the envelope is ceramic with the high voltage section potted to increase the high voltage stand off.

	Specification
Envelope	Ceramic
Be Window	.003" (.076 mm) Thick
Anode	Copper body with the target material attached
Standard Target Materials	5
Rhoo	dium, Palladium, Tungsten, Titanium, Moly, Copper, Silver, Chrome
Target Angle	
Focal Spot	
Maximum Anode Dissipa	ation with 10 cfm forced air cooling
Filament Characteristics	
Maximum Anode Potenti	ial 50 kVp Maximum D.C. (Titanium - 20 kV
Maximum Tube Current	Refer to Emission and Rating Char
Cooling Method	Forced air convection
Weight	

6128 Rev E 01/06





Modern Handheld, Portable XRF Analyzer

Main Features

- Ergonomically designed, ideal form factor
- Silicon "p-i-n" detector, < 200 eV
- 40 kV, 50 uA transmission anode low power x-ray source
- Lightweight

3 lbs (1.36 kg)

- · Long, 12+ hours battery use
- Large touch screen LC display
 2.25" x 3" (57 mm x 76 mm)
- 4096 channels MCA
- optimized for speed ASIC based DSP
- Integrated touch screen
- Integrated bar code scanner
- Integrated wireless communication link
- Fastest FP
- FP not sensitive to shape and surface irregularities
- No transport restrictions

Thermo SCIENTIFIC

Thermo Fisher

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Plate 1 Experimental layout. (1) measuring head (gas counter), (2) preamplifier, (3) measuring head (NaI(Tl) counter), (4) amplifier, (5) pulse height analyser.



X-RAY TUBES MUST BE COLLIMATED. IN MANY CASES THE TUBE MUST BE ALSO FILTERED TO SELECT AN OUTPUT BEAM OF PROPER ENERGY AND INTEN-SITY, TO EXCITE A GIVEN ELEMENT WITH GIVEN CONCENTRATION AND IN A GIVEN MATRIX









XRF is not able to:

-detect low atomic number elements (up to 15 approximately)
-detect chemical bonds
-carry out volume analysis (in many cases)



X-RAY DETECTORS

LABORATORY XRF-SYSTEMS -Si(Li) -HpGe Energy resolution about 130 eV at 5.9 keV High geometrical efficiency About 100% intrinsic efficiency

PORTABLE XRF-SYSTEMS -thermoelectrically cooled Si-PIN or Si-drift Energy resolution about 140 eV at 5.9 keV low geometrical efficiency intrinsic efficiency depending on the energy

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property amplified and formed to give Gaussian pulses. These pulses are finally converted into numbers and classified with a pulse height analyzer that produces a "spectrum".





Fig. 5.1. – Photography of typical X-ray detectors. From left a Xe gas proportional counte (1), a Ne gas proportional counter (2), a small X-ray NaI(Tl) detector for tomography (3), a Al-window NaI(Tl) X-ray detector (4), an AMPTEK Si-PIN (5) and a HpGe (6).



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With regard to the distances and geometry source-sample-detector, it is worthwhile to note that while the distance source-sample is not affecting too much the fluorescence spectrum, the distance source-sample is critical for the low-energy part of the spectrum, where the air attenuation plays an important role.

Air thickness attenuating 50% of the radiation, and attenuation by 2 cm air versus energy are shown in Table 10.

Concerning the angles, the X-ray detector is generally put orthogonally to the sample surface, while the X-ray tube is located at about 30-45° according to the sizes.

Table 10- X-rays attenuation by air

E _X (keV)	Air thickness for 50% attenuation	Attenuation of 2 cm air
1	1.2 mm	100%
1.5	4.1 mm	97%
2	9.6 mm	74%
2.5	1.9 cm	55%
3	3.2 cm	35%
5	14.4 cm	10%



Figure 21 – Capillary collimators manufactured by IfG, Berlin, Germany, and principle of capillary optics, where 9c is the critical angle for total reflection [45].





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ENERGY-DISPERSIVE X-RAY FLUORESCENCE : ANALYSIS OF WORKS OF ART





FOLLOWING UNESCO INDICATIONS, ITALY HAS A CULTURAL HERITAGE BIGGER THAN ANY OTHER COUNTRY. **IT IS COMPOSED OF PAINTINGS** FRESCOS, MARBLES, MONUMENTS, STATUES, ALLOYS....STARTING FROM ABOUT 1500 BC. THIS CULTURAL HERITAGE NEEDS TO BE -PRESERVED -CONSERVED -RESTORED (WHEN NECESSARY) AND FIRST OF ALL

-ANALYZED

THE SCIENTIFIC AREA RELATED TO THE APPLICATION OF SCIENTIFIC METHODS AND TECHNIQUES TO STUDY WORKS OF ART IS CALLED ARCHAEOMETRY



Stamps

papers,

stones,

ART



Plate 1 Experimental layout. (1) measuring head (gas counter), (2) preamplifier, (3) measuring head (NaI(Tl) counter), (4) amplifier, (5) pulse height analyser.





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F

NON-DESTRUCTIVE ANALYSIS OF CHEMICAL ELEMENTS IN PAINTINGS AND ENAMELS

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1. INTRODUCTION

Several non-destructive methods of analysis take advantage of the more sophisticated techniques which are commonly used to-day in atomic and nuclear spectroscopy. The fact that it is possible to carry out non-destructive analyses of chemical elements gives new possibilities for the study of works of art. This paper deals with various applications of X-ray fluorescence analysis (XRF) to paintings and enamels.

In the past an XRF system needed large complex equipment. To-day simplified versions are available which consist of a radioactive source instead of an X-ray tube and of a nondispersive spectrometer, i.e. a proportional counter coupled with a pulse height multichannel analyser. In our apparatus the proportional detector (gas counter or NaI(T1) counter) and the exciting source form one unit. This 'measuring-head' weighs less than a kilogram and is the size of a tape-recorder microphone; the unit is connected by a flexible cable of variable length, to the multichannel analyser (figure 1). With a system of this kind one can conveniently delimit and analyse areas in the range 1–20 cm² (see section 2). To delimit extremely small areas (between 1 mm² and 1 μ m²), one has to employ more complex systems (see for instance Stolow *et al.* 1969).

When a mobile measuring head is not needed, one can use a semiconductor detector which has better resolution than a proportional counter and so considerably simplifies the interpretation of the X-ray spectrum (Bowman *et al.* 1966, Frankel 1969, 1970).

The XRF system is described in section 2 and the various analyses performed on paintings and enamels are presented and discussed in sections 3, 4 and 5.

2. EXPERIMENTAL DETAILS

Plate 1 illustrates the XRF unit complete with two measuring heads: one of these uses a proportional counter filled with Kr+10% CH₄; the other, a NaI(T1) scintillator. The dimensions of the system, made up of standard laboratory equipment, can be drastically reduced by using more compact standard electronics; in this way a transportable system can easily be obtained.

The characteristics of the isotopic sources used are summarized in table 1. A ³H source was used to excite X-ray fluorescence in light elements (from sulphur to zinc); ²⁴¹Am and ¹⁴⁷Pm sources were employed to excite medium and heavy elements and a ⁵⁷Co source was

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Plate 1 Experimental layout. (1) measuring head (gas counter), (2) preamplifier, (3) measuring head (NaI(Tl) counter), (4) amplifier, (5) pulse height analyser.





EDXRF-ANALYSIS CAN BE THEREFORE

- PREVIOUS RESTORATION AREAS
- TYPICAL PIGMENTS USED BY AN ARTIST IN A GIVEN PERIOD OF TIME
 FAKES
- POLLUTION EFFECTS ON THE SURFACE (PRESENCE OF S AND/OR CI DUE TO BURNING OF WOOD, COAL, GASOLINE AND PRODUCING GYPSUM WHICH BLACKENS THE PAINTING





Identification of fakes

In some cases the classification of the pigments employed by an artist in a well defined period of time may help in the identification of fakes. An example of this point is related to the analysis of De Chirico paintings of his last period, and of paintings attributed to De Chirico (of the same period) and subject to judicial skill.

- 15 paintings of De Chirico have been analyzed, showing common Characteristics, such as:
- -preparation based on the use of lead white and zinc white;
- -a systematic use of lead;
- -red colours based on the use of cinnabar (HgS);
- -moderate use of organic pigments.

On the north coast of present-day Perù evolved between 50 A.D. and 700 A.D. approximately the MOCHE civilization. It was an advanced culture and the Moche were very sophisticated metalsmiths. They are considered the finest producers of jewels of the central Andes, both in terms of their technological sophistication and their beauty.

The Moche culture was influenced by the Chavin and Vicus civilizations (1000-200 B.C.) and strongly influenced the Sican (750-1375 A.D.) and Chimù (1000-1460 A.D.).



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The Moche metalworking ability was impressively Demonstrated by the excavations of the "Tumbas Reales de Sipan", discovered by Walter Alva and coworkers in 1987. The spectacular gold, silver and copper funerary ornaments are now in the namesake Museum, in Lambayeque.





A. Bustamante, J. Fabian Universidad Nacional Mayor de S. Marcos Lima, Peru (oro de Sipan, Sican, Vicus) C. Calza, M. dos Anjos, R. Lopes COPPE, Universidade Federal do Rio de Janeiro (oro de Sipan e Sican) M.Rizzutto, USP Sao Paulo (oro Vicus 2009)



THREE POSSIBLE GOLD COMBINATIONS HAVE BEEN DETECTED :

GOLD (Au, Ag and Cu alloy)

GILDED COPPER (a Au-leaf of less than 1 micron overimposed to almost pure Cu)

TUMBAGA (a poor Au-alloy enriched by depletion gilding); Tumbagas of Cu (Cu+Au) and of Ag (Ag+Au) are known Gold leafs of 2-5 microns



GOLD MASK

FRONT SIDE Au=74.5% Ag= 23% Cu=2.5% BACK SIDE Au=64.5% Ag=20% Cu=15.5%

LEFT EYE Ag=91% Cu=5% Au=1.5% Br=2% **RIGHT EYE Copper**

SOLDERING MAINLY ON Cu In some areas Cu+Ag









Museum inside the Palazzo. A summary of the results is also shown, where results on the horse, knight and original weldings are grouped.

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A summary of the Sn-Pb correlation obtained in cleaned areas is also shown.

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A FLUORESCENCIA DE RAIOS X E UMA TECNICA ANALITICA FACIL






MASK ON GILDED COPPER

GILDING COMPOSITION : Au=97.5% Ag=2.5% (Cu difficult to determine, because present as support)

GILDING THICKNESS : ~0.6 µm

17 . 16 18 15 -19 20 🕹 22 . 21



FACE COVERING, ON TUMBAGA



LEFT EYE: Au=47.5% Cu=45.5% Ag=8% RIGHT EYE Au=47.5% Cu=45.5% Ag=8% THICKNESS 2 μm

NOSE Au=52.5% Cu=34.5% Ag=13%

THICKNESS: 2.7 µm

MOUTH Au=49% Cu=34% Ag=17%

THICKNESS : 2.7 μm





FUNERARY MASK ON TUMBAGA (MUSEUM OF SICÁN)

NOSE : Au=51% Cu=37.5% Ag=9.5% THICKNESS: 8 μm

MAIN SHEET AND PENDANTS Au=34% Cu=57% Ag=7% THICKNESS: 5 μm

RED PIGMENT : CINNABAR

CLAMPS : ON TUMBAGA OR SILVERED COPPER

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	RESULTS OF	F THE ANA	ALYSIS OF	SIPAN ALLOYS:	UNIVERSITÀ degli STUDI di SASSARI		
	GOLD						
		Au(%)	Ag(%)	Cu(%)			
	Tomb n. 1 :	72.5	18.5	10			
	Tomb n.2 :	70	23	7			
	Tomb n.6 :	74	16	10			
	Mean value	70±7	20 ± 7	10 ± 4			
Mean value 70 ± 7 20 ± 7 10 ± 4 SILVERAg(%)Cu(%)Au(%)							
		Ag(%)	Cu(%)	Au(%)			
	Mean value	92.5 ± 3	4.5±2	3±1.5			
	TURQUOISE						
		Cu(%)	Fe(%)	Zn(%)			
	Mean value	81.5±6	10 ± 4	8.5±3.5			
COPPER							
	Mean value	$Cu \ge 99$.	5%				
	SOLDERING						
Copper or silver/copper alloy 78							
					10		

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COMPARISON BETWEEN SIPAN (400 A.C.) AND SICAN UK (>750 A.C.)

SIPAN	Au(%)	Ag(%)	Cu(%)	Pb(%)	Br(%)	As(%)	Fe(%)
GOLD:	70	20	10	-		99	
SILVER:	3	92	5	2 - mili			1000 Con
COPPER :	St.	in the second	> 99.5	-			Stra- 4
GILDING :	9	2.5		-	-	3.2	-
TUMBAGA:	50	13	37		1 -		-
SICAN							
GOLD	62	32	6	- A	- 22	- 1	-
SILVER	0.5	94	3.7	0.8	- 1		-
COPPER	-300	-	97.9		-	0.9	2.4
GILDING	66	35	?		1	Terrete	-
TUMBAGA	34	7	57		/	-	















Command stick of the "Señor de Sipan" on gold, with a support on silver

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In the case of Sipan alloys (gold, silver, copper alloys), Different situation have been observed:

-gold, composed as usually of gold, silver and copper; -gilded copper;

-tumbaga gold (poor Au-alloys enriched at the surface);

-silver, composed as usually of silver and copper (but also gold is generally present);

-tumbaga silver;

-copper, generally almost pure.

How gold, gilded copper and tumbaga can be differentiated ? How can be determined the gilding thickness ?

-by accurately measuring the $K\alpha/K\beta$ -ratio emitted by the deeper element (for example Cu or Ag for gilded copper or gilded silver respectively); -by plotting the ratio between (Cu/Au) or (Ag/Au) counts -by carrying out EDXRF-measurements at various angles source-sample-detector, to help in the thickness determination.















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RESULTS O	F THE ANA	ALYSIS OF	SIPAN ALLOYS:	UNIVERSITÀ			
GOLD di SASSARI							
1 / / / / / / / / / / / / / / / / / / /	Au(%)	Ag(%)	Cu(%)				
Tomb n. 1 :	72.5	18.5	10				
Tomb n.2 :	70	23	7				
Tomb n.6 :	74	16	10				
Mean value	70 ± 7	20±7	10±4				
SILVER							
	Ag(%)	Cu(%)	Au(%)				
Mean value	92.5 ± 3	4.5 ± 2	3 ± 1.5				
	TUROUOISE						
	Cu(%)	Fe(%)	Zn(%)				
Mean value	81.5 ± 6	10 ± 4	8.5±3.5	-			
COPPER							
Mean value	Mean value $Cu > 99.5\%$						
	SOLDERING						
Copper or silver/copper alloy							

Au-thickness vs measurement N.
























A summary of the Sn-Pb correlation obtained in cleaned areas is also shown.

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11:

ADDITIONAL APPLICATIONS OF X-RAY FLUORESCENCE

TO IDENTIFY: -NANOPARTICLES IN BIOLOGICAL MATERIALS -NANOPARTICLES IN FOOD, PHARMACEUTICALS AND ENVIRONMENTAL SAMPLES -INDUSTRIAL PRODUCTS

THE TECHNIQUE IS: -NON DESTRUCTIVE -SIMPLE -THE RELATED EQUIPMENT IS PORTABLE -SPECIFIC



13:

X-RAY FLUORESCENCE TO STUDY TRACE ELEMENTS IN SOIL AND CONTAMINATED SOIL











PRINCIPALI RAGGI X

ELEMENTO	Κα	Кβ	La	Lβ	Lγ
SODIO	1.04				
MAGNESIO	1.25				
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ARGENTO	22.2	24.9	2.98	3.2	
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ANTIMONIO	26.4	29.7	3.6	4.0	
BARIO	32.2	36.4	4.45	5.0	
TUNGSTENO	59.3	67.2	8.4	9.9	
ORO	68.8	78.0	9.7	11.5	
MERCURIO	70.8	80.3	9.95	11.9	
PIOMBO	75	84.9	10.5	12.6	
URANIO	98.4	111.3	13.5	17.5	







VF-50 Shielded

VF-50J Industrial X-Ray Tube

APPLICATION

The VF-50 series x-ray tube is a beryllium window x-ray tube designed for use as a radiation source for x-ray fluorescence systems.

CONSTRUCTION

The beryllium x-ray window is located at the end of the tube and the beam is projected along the longitudinal axis of the tube. The cathode operates at ground potential and the envelope is ceramic with the high voltage section potted to increase the high voltage stand off.

Spec	cification
Envelope	Ceramio
Be Window	
Anode	. Copper body with the target material attached
Standard Target Materials	
Rhodium, Palladium, Tu	ungsten, Titanium, Moly, Copper, Silver, Chrome
Target Angle	
Focal Spot	
Maximum Anode Dissipation with 10 cfm fo	rced air cooling
Filament Characteristics	
Maximum Anode Potential	50 kVp Maximum D.C. (Titanium - 20 kV)
Maximum Tube Current	Refer to Emission and Rating Chart
Cooling Method	Forced air convection
Weight	

6128 Rev E 01/06











Applications

- RoHS/WEEE
- · Alloy sorting
- Soil analysis
 Environmental
- Lead in paint
- Plastics analysis
- Material ID
- Security

Handheld Imaging

- Medical/Dental
- Material ID
- Security
- Bench top EDXRF
- Instrument Calibration
- Micro-Fluorescence Micro-Diffraction



50kV MAGNUM[®] X-ray Tubes

The MAGNUM* x-ray tube is now available in a 50kV package. The MAGNUM 50kV x-ray tube is a low power, miniature x-ray tube used for a variety of applications including handheld and benchtop instrumentation. MAGNUM x-ray tubes are small, lightweight, and can be packaged into custom enclosures.

Benefits

- Small, compact design Lightweight Close coupling of collimator & target Stable output Low power consumption Low spectral contamination High x-ray output Customizable configurations
- Close coupling of source to detector Portable, versatile t Efficient utilization of x-rays Low detection limit Long battery life No unwanted peaks Short sampling time Flexible form factor

Standard Package Includes:

- Transmission Target (End Window)
- · MAGNUM tube potted in a brass shield
- High voltage power supply
- · High voltage wire length is 11.5 inches

Customizable Options:

- · Target materials and thickness
- Tube shield design
- Power supply packaging
- High voltage wiring length
- · Integrated tube and power supply

.



Modern Handheld, Portable XRF Analyzer

Main Features

- Ergonomically designed, ideal form factor
- Silicon "p-i-n" detector, < 200 eV
- 40 kV, 50 uA transmission anode low power x-ray source
- Lightweight
 - 3 lbs (1.36 kg)
- · Long, 12+ hours battery use
- Large touch screen LC display
 - 2.25" x 3" (57 mm x 76 mm)
- 4096 channels MCA
- optimized for speed ASIC based DSP
- Integrated touch screen
- Integrated bar code scanner
- Integrated wireless communication link
- Fastest FP
- FP not sensitive to shape and surface irregularities
- No transport restrictions



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